Receipt date: 06/01/2009 10815400 - GAU: 2829

Appl. no. 10/815,400 IDS dated June 1, 2009

Modified Form PTO/SB/08A

Substitute for form 1449A/PTO	Complete If Known	
	Application Number	10/815,400
INFORMATION DISCLOSURE	First Named Inventor	Eldridge et al.
STATEMENT BY APPLICANT	Filing Date	March 31, 2004
(use as many sheets as necessary)	Group Art Unit	2829
	Examiner Name	Ernest F. Karlsen
No. of Refs.: 3	Attorney Docket No.	P71C2-US

U.S. PUBLISHED PATENT DOCUMENTS							
Examiner	Cite	U.S. Patent Docu	ıment	Name of Patentee or	Publ./Issue	Related <sup>#</sup>	Copy
Initials*	No. <sup>1</sup>	Number Ki	ind Code <sup>2</sup>	Applicant	Date		Enclosed
	1.	3806801		Bove	4/23/1974		No***

	OTHER PRIOR ART – NONPATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	$T^2$	Copy Enclosed	
	2.	Taber et al. "Vertical Probing Experiences," International SEMATECH Wafer Probe Council, 2003 Southwest Test Workshop (2003) 29 pages		Yes	
	3.	Mann, "'Leading Edge' Of Wafer Level Testing," 2004 Southwest Test Workshop (2004) 64 pages		Yes	

Examiner   /Ernest F. Karlsen/	Date Considered	08/26/2009
--------------------------------	--------------------	------------

<sup>\*</sup> EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

<sup>\*\*</sup> Reference cited in parent application US Serial No. \_\_\_\_\_\_. CFR § 1.98(d)

<sup>\*\*\*</sup> Pre-OG Notice By Deputy Commissioner Stephen G. Kunin dated July 11, 2003 waiving the requirement to file copies of US patent publications in applications filed after June 30, 2003.

<sup>&</sup>amp; Notice dated October 19, 2004 by Deputy Commissioner for Patent Examination Policy waiving requirement to file copies of pending US patent applications if the applications are stored in the USPTO's IFW system.

<sup>#</sup> Commonly owned US patent or application whose subject matter may be related to the subject matter of the instance patent application.